

PRELIMINARY

July 1998

FM27C010L 1,048,576-Bit (128Kx8) Low Power Fast EPROM

General Description

The FM27C010 is a low-power 1Mbit, 5V-only one-time-programmable (OTP) read-only memory (EPROM), organized into 128K words with 8 bits per word. Any byte can be accessed in less than 45ns, eliminating the need for WAIT states in high-performance microprocessor systems. The FM27C010 has separate Output Enable (\overline{OE}) and Chip Enable (\overline{CE}) controls which eliminate bus contention issues.

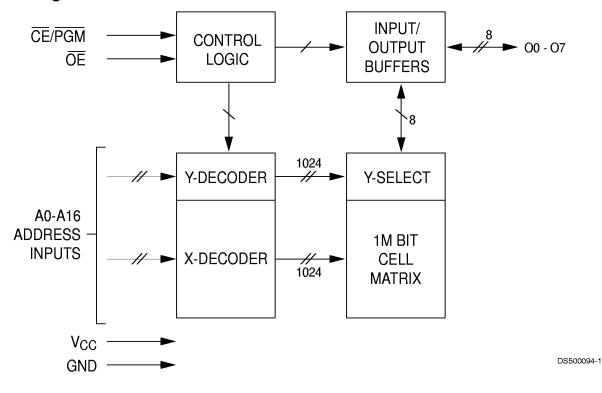
The FM27C010 is one member of a fast EPROM family which range in densities from 256Kb to 1Mb.

Features

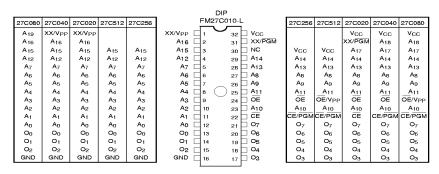
- Fast Read Access Time: -45 and -55ns
- Single 5V Power Supply
- Low Standby Current: 1µA (Typical)

- Programming Voltage +12.75V
- Typical programming time 50µs
- Low Power CMOS Operation
- 30mA Operation (Max.)
- CMOS-and TTL-Compatible I/O
- High-Reliability CMOS Technology
- Latch-Up Immunity to 100mA from -1V to V_{CC} + 1V
- Two-Line Control (OE & CE)
- Standard Product Identification Code
- JEDEC Standard Pinout
 - 32-pin PDIP
 - 32-pin PLCC
- 32-pin TSOP (Type 1)
- Commercial and Industrial Temperature Ranges

Block Diagram



Connection Diagrams



DS500094-2

Note: Compatible EPROM pin configurations are shown in the blocks adjacent to the FM27C010 pins.

Commercial Temperature Range (0°C to +70°C) $V_{CC} = 5V \pm 10\%$

Parameter/Order Number	Access Time (ns)
FM27C010 N, T, V 45 L	45
FM27C010 N, T, V 55 L	55

Pin Names

Pin Name	Function
A ₀ -A ₁₆	Addresses
O ₀ -O ₇	Outputs
PGM	Program
ŌĒ	Output Enable
NC	No Connect
CE	Chip Enable

Industrial Temperature Range (-40°C to +85°C) V_{CC} = 5V ± 10%

Parameter/Order Number	Access Time (ns)
FM27C010 NE, TE, VE 45 L	45
FM27C010 NE, TE, VE 55 L	55

Note 1: All versions are guaranteed to function for slower speeds.

Package Types:

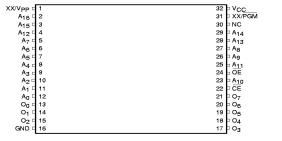
N = Plastic DIP Package

T = TSOP Package

V = PLCC Package

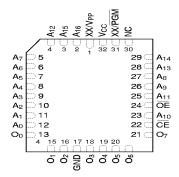
All packages conform to the JEDEC standard

TSOP Pin Configuration



DS500094-3

PLCC Pin Configuration



DS500094-4

Absolute Maximum Ratings (Note 1)

Storage Temperature -65°C to +125°C

All Input Voltage except A9

with Respect to Ground -0.6V to +7V

V_{PP} and A9 with Respect to Ground -0.6V to +13.5V

V_{CC} Supply Voltage with

Respect to Ground -0.6V to +7V

ESD Protection

(MIL St. 883, Method 3015.2) >2000V

All Output Voltages with Respect to Ground

-0.6V to $V_{\rm CC}$ + 0.5V

Operating Range

Range	Temperature (T _C)	V _{cc}	Tolerance
Commercial	0°C to +70°C	+5V	±10%
Industrial	-40°C to +85°C	+5V	±10%

Read Operation

DC Electrical Characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
V _{OH}	Output High Voltage	I _{OH} = -0.4mA	2.4		٧
V _{OL}	Output Low Voltage	I _{OL} = 2.1mA		0.45	V
V _{IH}	Input High Voltage		2.0	V _{CC} + 0.5	٧
V _{IL}	Input Low Voltage		-0.3	0.8	V
I _{LI}	Input Leakage Current	V _{IN} = 0 to V _{CC}	-5	5	μΑ
I _{LO}	Output Leakage Current	V _{OUT} = 0 to V _{CC}	-10	10	μА
I _{CC3}	V _{CC} Power-Down Current	$\overline{CE} = V_{CC} \pm 0.3V$		10	μΑ
I _{CC2}	V _{CC} Standby Current	CE = V _{IH}		1	mA
I _{CC1}	V _{CC} Active Current	$\overline{CE} = V_{IL}$, $f = 5MHz$, $I_{OUT} = 0mA$		30	mA
I _{PP}	V _{PP} Supply Current Read	CE = OE = V _{IL} , V _{PP} = V _{CC}		100	μА

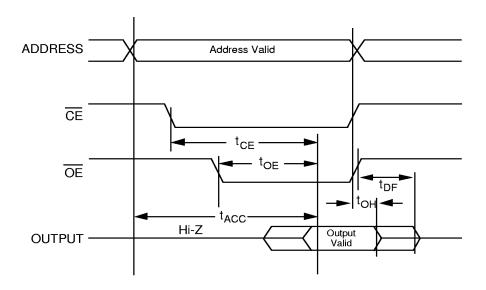
AC Electrical Characteristics

Symbol	Parameter	-4	15	-5	Unit	
-		Min	Max	Min	Max	
t _{ACC}	Address to Output Delay		45		55	ns
t _{CE}	CE to Output Delay		45		55	ns
t _{OE}	OE to Output Delay		25		25	ns
t _{DF}	OE or CE High to Output Float, whichever occurred first		20		20	ns
t _{OH}	Output Hold from Address, CE or OE, Whichever Occurred First	0		0		ns

Capacitance $T_A = 25^{\circ}C$, f = 1MHz

Symbol	Parameter	Conditions	Тур	Max	Units
C _{IN}	Input Capacitance Except OE/V _{PP}	V _{IN} = 0V	8	12	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V	8	12	pF
V_{PP}	OE/V _{PP} Input Capacitance	V _{IN} = 0V	18	25	pF

AC Waveforms for Read Operation



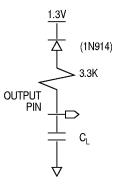
DS500094-5

Output Test Waveforms and Measurements

45 and 55 Devices

AC DRIVING LEVELS
$$0.0V$$
 $1.5V$ AC MEASUREMENT LEVEL $t_{\rm R}, t_{\rm F} < 5 \, \rm ns \, (10\% \, to \, 90\%)$

Output Test Load



Note:C_L = 30pF including jig capacitance

DS500094-6

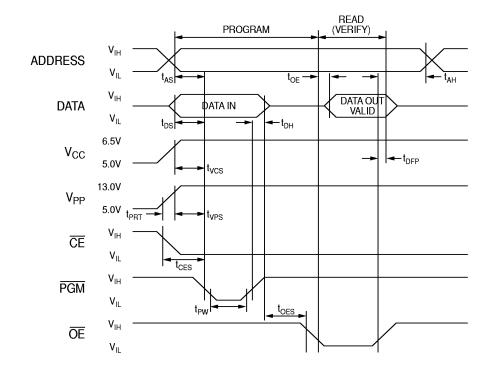
DC Programming Characteristics

			Liı		
Sumbol	Parameter	Test Conditions	Min	Max	Units
ILI	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		5.0	μΑ
V _{IL}	Input Low Level		-0.5	0.8	V
V _{IH}	Input High Level		2.4	V _{CC} + 0.5	V
V _{OL}	Output Low Voltage	I _{OL} = 2.1 mA		0.45	V
V _{OH}	Output High Voltage	I _{OH} = -400μA	2.4		٧
I _{CC2}	V _{CC} Supply Current			40	mA
I _{PP2}	V _{PP} Supply Current	CE = PGM = V _{IL}		10	mA
V _{ID}	A9 Product ID Voltage		11.5	12.5	٧
V _{PP}	Programming Supply Voltage		12.5	13.0	V
V _{CC}	Power Supply Voltage		6.25	6.75	٧

Switching Programming Characteristics (T $_{A}$ = +25 $^{\circ}$ \pm 5 $^{\circ}C)$

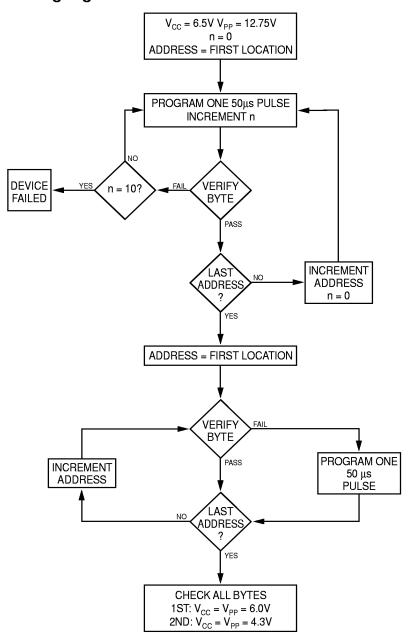
Symbol	Parameter	Min	Max	Units
t _{AS}	Address Setup Time	1		μs
t _{OES}	OE/V _{PP} Setup Time	1		με
t _{DS}	Data Setup Time	1		με
t _{AH}	Address Hold Time	0		μs
t _{DH}	Data Hold Time	1		μs
t _{DFP}	Output Enable to Output Float Delay	0	130	ns
t _{VPS}	V _{PP} Setup Time	1		μs
t _{PW}	PGM Program Pulse Width	20	105	μs
t _{VCS}	V _{CC} Setup Time	1		με
t _{CES}	CE Setup Time	1		μs
t _{OE}	Data Valid from OE		150	ns

Programming Waveforms



DS500094-7

Turbo Programming Algorithm Flow Chart



DS500094-8

Figure 1

Note: National Semiconductor NM27C010 Fast Programming Algorithm may also be used.

Functional Description

Device Operation

The modes of operation of the EPROM are listed in Table 1. The power supplies required are $V_{\rm CC}$ and $\overline{\rm OE/V_{PP}}.$ The $\overline{\rm OE/V_{PP}}$ power supply must be at 12.75 during the three programming modes, and must be at 5V in the other three modes. The $V_{\rm CC}$ power must be at 6.5V during the three programming modes, and at 5V in the other three modes.

Read Mode

The EPROM has two control functions, both of which must be logically active in order to obtain data at the outputs. Chip Enable (CE/PGM) is the power control and should be used for device selection. Output Enable (OE/V_{PP}) is the output control and should be used to gate data to the output pins, independent of device selection. Assuming that addresses are stable, address access time (t_{ACC}) is equal to the delay from \overline{CE} to output (t_{CE}). Data is available at the outputs t_{OE} after the falling edge of \overline{OE} , assuming that \overline{CE} has been low and addresses have been stable for at least t_{ACC} - t_{OE}.

Standby Mode

The FM27C010 has CMOS standby mode which reduces the maximum $V_{\rm CC}$ current to 1µA (typical). It is placed in CMOS standby when CE is at $V_{\rm CC}\pm 0.3V$. The FM27C010 also has a TTL standby mode which reduces the maximum $V_{\rm CC}$ current to 1.0 mA. It is placed in TTL standby when CE is at $V_{\rm IH}$. When in standby mode, the outputs are in a high-impedance state, independent of the OE input.

Two-Line Output Control Function

To accommodate multiple memory connections, a two-line control function is provided to allow for:

- 1. Low memory power dissipation,
- 2. Assurance that output bus contention will not occur.

It is recommended that \overline{CE} be decoded and used as the primary device-selection function, while \overline{OE} be made a common connection to all devices in the array and connected to the READ line from the system control bus. This assures that all deselected memory devices are in their low-power standby mode and that the output pins are only active when data is desired from a particular memory device.

Programming

Caution: Exceeding 13.5V on pin 22 (OE/ V_{PP}) will damage the EPROM.

Initially, and after each erasure, all bits of the EPROM are in the "1's" state. Data is introduced by selectively programming "0's" into the desired bit locations. Although only "0's" will be programmed, both "1's" and "0's" can be presented in the data word. The only way to change a "0" to a "1" is by ultraviolet light erasure.

The EPROM is in the programming mode when the OE/ V_{PP} power supply is at 12.75V. it is required that at least a 0.1 μ f capacitor be placed across V_{CC} to ground to suppress spurious voltage transients which may damage the device. The data to be programmed is applied 8 bits in parallel to the data output pins. The levels required for the address and data inputs are TTL.

When the address and <u>data are stable</u>, an active low, TTL program pulse is applied to the CE/PGM input. A program pulse must be applied at each address locaiton to be programmed.

The EPROM is programmed with the Turbo Programming Algorithm shown in Figure 1. Each Address is programmed with a series of $50\mu s$ pulses until it verifies good, up to a maximum of 10 pulses. Most memory cells will program with a single $50\mu s$ pulse. The Turbo Programming Algorithm will be available in early Quarter 1, 1998. Until this program is installed the EPROM may be programmed using National Semiconductor NM27C010 Fast Programming Algorithm.

The EPROM must not be programmed with a DC signal applied to the $\overline{\text{CE/PGM}}$ input.

Programming multiple EPROM in parallel with the same data can be easily accomplished due to the simplicity of the programming requirements. Like inputs of the parallel EPROM may be connected together when they are programmed with the same data. A low level TTL pulse applied to the CE/PGM input programs the paralleled EPROM.

Program Inhibit Mode

Programming of multiple FM27C010 in parallel with different data is also easily accomplished by using the Program Inhibit Mode. Except for CE, all like inputs of the parallel FM27C010 may be common. A TTL low-level program pulse appled to a FM27C010 CE input with $\overline{\text{OE/V}_{PP}} = 12.75 \pm 0.25 \underline{\text{V}}_{\text{will}}$ program that FM27C010. A high-level CE input inhibits the other FM27C010 from being programmed.

Program Verify Mode

Verification should be performed on the programmed bits to determine that they were correctly programmed. The verification should be performed with $\overline{OE/V_{PP}}$ and \overline{CE} at V_{IL} . Data should be verified at t_{DV} after the falling edge of \overline{CE} .

System Consideration

During the switch between active and standby conditions, transient current peaks are produced on the rising and falling edges of Chip Enable. The magnitude of these transient current peaks is dependent on the output capacitance loading of the device. At a minimum, a $0.1\mu F$ ceramic capacitor (high frequency, low inherent inductance) should be used on each device between V_{CC} and V_{SS} to minimize transient effects. In addition, to overcome the voltage drop caused by the inductive effects of the printed circuit board traces on EPROM arrays, a $4.7\mu F$ bulk electrolytic capacitor should be used between V_{CC} and V_{SS} for each eight devices. The location of the capacitor should be close to where the power supply is connected to the array.

Mode Selection

The modes of operation of the FM27C010 are listed in Table 1. A single 5V power supply is required in the read mode. All inputs are TTL levels except for $V_{\rm PP}$ and A9 for device signature.

Functional Description (Continued)

Table 1. Mode Selection

Mode	CE	ΟE	PGM	Α0	A 1	A9	V _{PP}	Output
Read	V _{IL}	V _{IL}	X (Note 2)	Х	Х	Х	V _{CC}	D _{OUT}
Output Disable	V _{IL}	V _{IH}	Х	Х	Х	Х	V _{CC}	High Z
Standby (TTL)	V _{IH}	X	Х	Х	Х	Х	V _{CC}	High Z
Standby (CMOS)	$V_{CC} \pm 0.3V$	Х	Х	Х	Х	Х	V _{CC}	High Z
Program (Note 4)	V _{IL}	V _{IH}	V _{IL}	Х	Х	Х	V _{PP}	D _{IN}
Program Verify	V _{IL}	V _{IL}	V _{IH}	Х	Х	Х	V _{PP}	D _{OUT}
Program Inhibit	V _{IH}	Х	Х	Х	Х	Х	V _{PP}	High Z
Manufacturer Code (Note 3)	V _{IL}	Х	V _{IL}	V _{IL}	V _{IH}	VH (Note 1)	V _{CC}	
Device Code (Note 3)	V _{IL}	Х	V _{IH}	V _{IH}	V _{IH}	VH (Note 1)	V _{CC}	

Note 1: $VH = 12.0V \pm 0.5V$. Note 2: $X = Either V_{IH}$ or V_{IL}

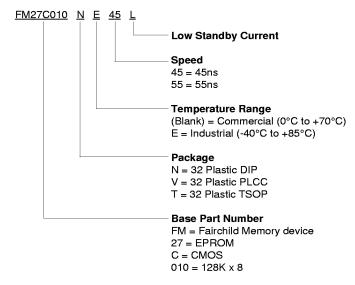
Note 3: For Manufacturer Code and Device Code, A1 = V_{IH} When A1 = V_{IL} , both codes will read 7F.

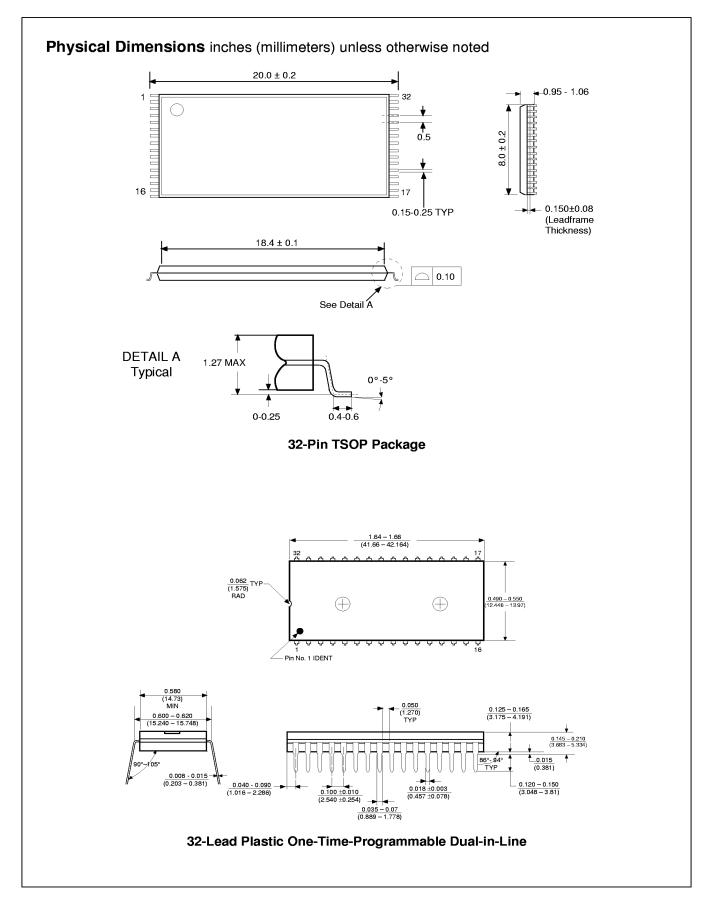
Note 4: See DC Programming Characteristics for $V_{\rm PP}$ voltage during programming.

Table 2. Manufacturer's Identification Code

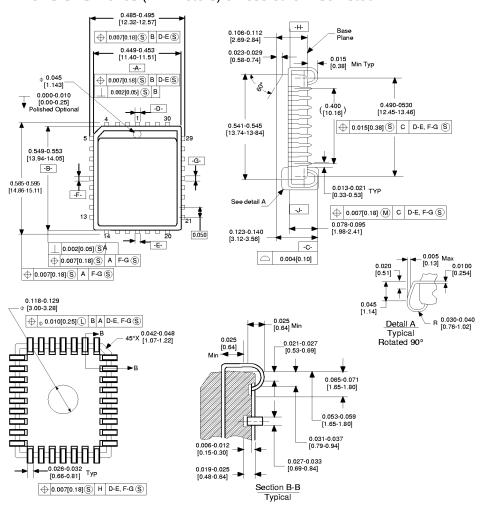
Pins Code	A 0	A 1	O 7	O 6	O 5	O 4	O 3	O 2	O 1	O 0	Hex Data
Manufacturer	0	1	0	0	0	1	1	1	0	0	1C
Device Type	1	1	0	0	0	0	0	0	0	1	01
Continuation	0	0	0	1	1	1	1	1	1	1	7F
	1	0	0	1	1	1	1	1	1	1	7F

Ordering Information





Physical Dimensions inches (millimeters) unless otherwise noted



32-Lead Plastic Leaded Chip Carrier (PLCC)
Package Number VA32A

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